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JC530 U.S. PTO  
09/430132  
10/09/87

Navy Case No. 70,840

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application:  
Keith A. Snail  
Kevin L. Carr  
For: INFRARED INTEGRATING SPHERE

INFORMATION DISCLOSURE STATEMENT UNDER  
37 C.F.R. Section 1.97

Honorable Commissioner of Patents and Trademarks  
Washington, D. C. 20231

Sir:

The Applicants wish to make of record the documents cited hereinbelow which are believed to be the most relevant concerning the invention as claimed in the above-identified Application.

Copies of the documents are attached hereto, save for the first two documents listed, which are filed herewith as attachments "A" and "B" respectively of the "Declaration of Keith A. Snail.

These documents are not necessarily a complete listing of all information known to the Applicants. The listing includes only that information which, in the reasonable opinion of the Applicants, is relevant to the claimed invention.

These documents are as follows:

1. K.A. Snail and K.L. Carr, "Optical Design of an Integrating Sphere-Fourier Transform Spectrophotometer (FTS) Emissometer," SPIE Conference on Infrared Optics, Vol. 643, dated May, 1986, first disseminated October 13, 1986 (cf. said Declaration of Snail, supra). This paper may be pertinent to his application because it discusses subject matter of the invention--but n.b. the paper's distribution date.
2. K.A. Snail and Kevin L. Carr, "Optical Design of an Integrating Sphere-FTS Emissometer", which is constituted by viewgraphs corresponding to the subject matter of document no. 1, supra. N.b. in said declaration of Snail that these viewgraphs were not disseminated.
3. D.K. Edwards et al., "Integrating Sphere for Imperfectly Diffuse Samples", Applied Optics, 51, 1279 (ca. 1960). This paper provides background for the invention; N.b. the discussion of center-mounted samples in integrating spheres. Of particular interest is Figure 4.
4. K. Gindele et al., "Spectral Reflectance Measurements Using an Integrating Sphere in the Infrared", Applied Optics, 24, 1757 (1985), which provides background for integrating spheres, especially techniques of making side wall measurements (see, e.g. Figure 1).

The Examiner is respectfully requested in accordance with Patent Office rules of practice to consider each of these documents before the first Office Action, and to indicate such in the first Office Action.

Respectfully submitted,  
Keith A. Snail  
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